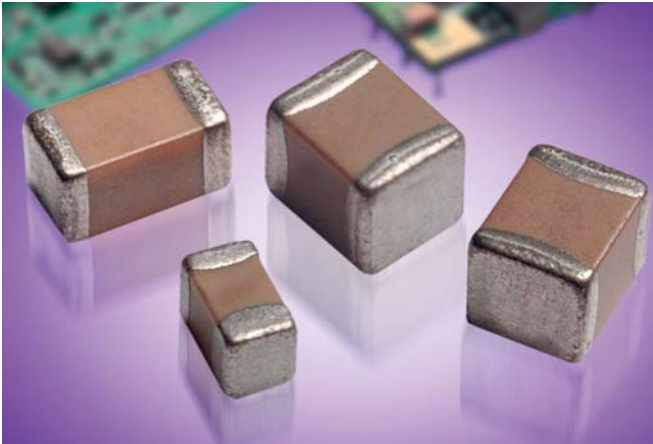


Y5V Dielectric

General Specifications



Y5V formulations are for general-purpose use in a limited temperature range. They have a wide temperature characteristic of +22% -82% capacitance change over the operating temperature range of -30°C to +85°C.

These characteristics make Y5V ideal for decoupling applications within limited temperature range.



PART NUMBER (see page 2 for complete part number explanation)

0805

Size
(L" x W")

3

Voltage
6.3V = 6
10V = Z
16V = Y
25V = 3
50V = 5

G

Dielectric
Y5V = G

104

Capacitance Code (In pF)
2 Sig. Digits + Number of Zeros

Z

Capacitance Tolerance
Z = +80 -20%

A

Failure Rate
A = Not Applicable

T

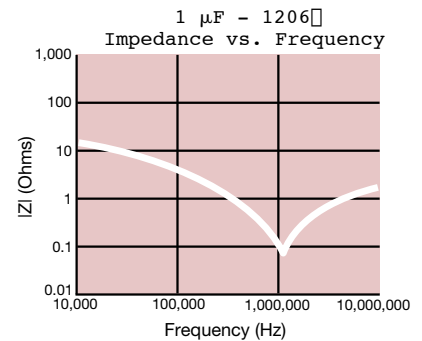
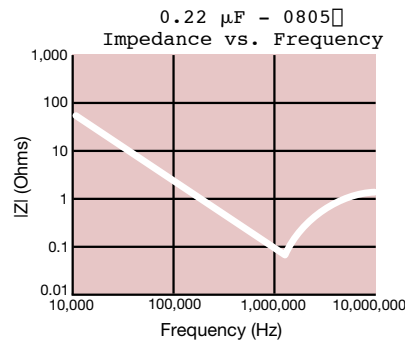
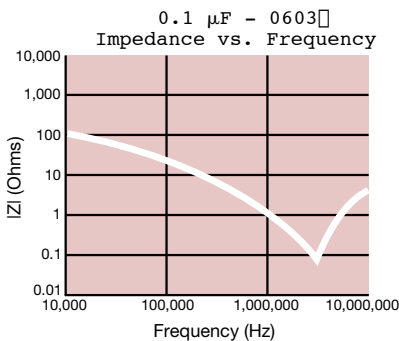
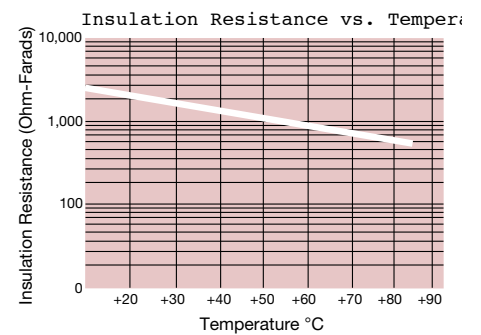
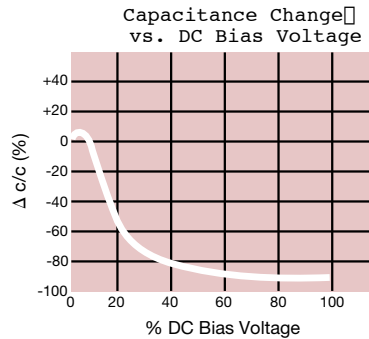
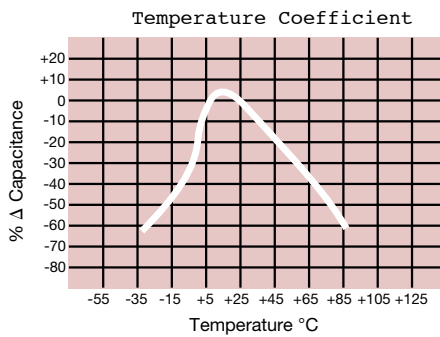
Terminations
T = Plated Ni and Sn

2

Packaging
2 = 7" Reel
4 = 13" Reel

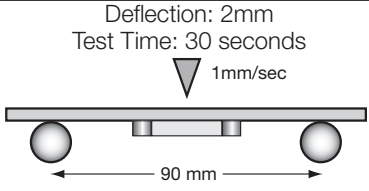
A

Special Code
A = Std. Product



Y5V Dielectric

Specifications and Test Methods

Parameter/Test		Y5V Specification Limits	Measuring Conditions	
Operating Temperature Range		-30°C to +85°C	Temperature Cycle Chamber	
Capacitance		Within specified tolerance	Freq.: 1.0 kHz \pm 10% Voltage: 1.0Vrms \pm .2V For Cap > 10 μ F, 0.5Vrms @ 120Hz	
Dissipation Factor		\leq 5.0% for \geq 50V DC rating \leq 7.0% for 25V DC rating \leq 9.0% for 16V DC rating \leq 12.5% for \leq 10V DC rating		
Insulation Resistance		10,000M Ω or 500M Ω - μ F, whichever is less	Charge device with rated voltage for 120 \pm 5 secs @ room temp/humidity	
Dielectric Strength		No breakdown or visual defects	Charge device with 300% of rated voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max)	
Resistance to Flexure Stresses	Appearance	No defects	Deflection: 2mm Test Time: 30 seconds 	
	Capacitance Variation	\leq \pm 30%		
	Dissipation Factor	Meets Initial Values (As Above)		
	Insulation Resistance	\geq Initial Value x 0.1		
Solderability		\geq 95% of each terminal should be covered with fresh solder	Dip device in eutectic solder at 230 \pm 5°C for 5.0 \pm 0.5 seconds	
Resistance to Solder Heat	Appearance	No defects, <25% leaching of either end terminal	Dip device in eutectic solder at 260°C for 60 seconds. Store at room temperature for 24 \pm 2 hours before measuring electrical properties.	
	Capacitance Variation	\leq \pm 20%		
	Dissipation Factor	Meets Initial Values (As Above)		
	Insulation Resistance	Meets Initial Values (As Above)		
	Dielectric Strength	Meets Initial Values (As Above)		
Thermal Shock	Appearance	No visual defects	Step 1: -30°C \pm 2°	30 \pm 3 minutes
	Capacitance Variation	\leq \pm 20%	Step 2: Room Temp	\leq 3 minutes
	Dissipation Factor	Meets Initial Values (As Above)	Step 3: +85°C \pm 2°	30 \pm 3 minutes
	Insulation Resistance	Meets Initial Values (As Above)	Step 4: Room Temp	\leq 3 minutes
	Dielectric Strength	Meets Initial Values (As Above)	Repeat for 5 cycles and measure after 24 \pm 2 hours at room temperature	
	Load Life		No visual defects	Charge device with twice rated voltage in test chamber set at 85°C \pm 2°C for 1000 hours (+48, -0)
Load Humidity	Appearance	No visual defects	Remove from test chamber and stabilize at room temperature for 24 \pm 2 hours before measuring.	
	Capacitance Variation	\leq \pm 30%		
	Dissipation Factor	\leq Initial Value x 1.5 (See Above)		
	Insulation Resistance	\geq Initial Value x 0.1 (See Above)		
	Dielectric Strength	Meets Initial Values (As Above)		
Load Humidity	Appearance	No visual defects	Store in a test chamber set at 85°C \pm 2°C/ 85% \pm 5% relative humidity for 1000 hours (+48, -0) with rated voltage applied.	
	Capacitance Variation	\leq \pm 30%		
	Dissipation Factor	\leq Initial Value x 1.5 (See above)		
	Insulation Resistance	\geq Initial Value x 0.1 (See Above)		
	Dielectric Strength	Meets Initial Values (As Above)		

